

## SPREADING RESISTANCE MEASUREMENT SYSTEM

- Single point, Contact Type by TOW Kinematically-Mounted Probe
- For slanting polished sample of semiconductor
- Resistivity map with depth direction, thickness of epitaxial, depth of PN junction and carrier density profiles
- Measure Range:
  - ✓ Spread Resistance ( $\Omega$ ): 1 to 10E9
  - ✓ Carrier Density (N-Type): 2E13 to 5E19 cm<sup>2</sup>
  - ✓ Carrier Density (P-Type): 2E14 to 7E19 cm<sup>2</sup>
- Sample Size: On Request

**SRS-2010**



### APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC, etc)
- Others: On Request

